

**Search Notes**

Application/Control No.

10/693,920

Examiner

DANH C. LE

Applicant(s)/Patent under  
Reexamination

FUJII ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
455	575.3	6/27/06	DCL
	575.4		
	418		
	90.1		
379	433.13		
	418		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search		6/27/06	DCL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST Search (US, US PUB, EPO, JPO DERWENT)	6/27/06	DCL
Inventor Name Search (check for double patenting)		